EX: Suppose that the circuits in some system have a lifetime that is exponentially distributed with parameter.). W= min \(\frac{2}{2}\trigon_{1}\trigon_{1}\trigon_{2}\trigon_{1}\trigon_{2}\trigon_{1}\trigon_{1}\trigon_{2}\trigon_{1}\trigon_{1}\trigon_{2}\trigon_{1}\trigon_{2}\trigon_{1}\trigon_{2}\trigon_{1}\trigon_{1}\trigon_{2}\trigon_{1}\trigon_{1}\trigon_{2}\trigon_{1}\trigon_{1}\trigon_{2}\trigon_{1}\trigon_{1}\trigon_{2}\trigon_{1}\trigon_{1}\trigon_{2}\trigon_{1}\trigon_{1}\trigon_{2}\trigon_{1}\trig_{1}\trigon_{1}\trigon_{1}\trigon_{1}\trigon_{1}\trigon_{1}\trigon_{1}\trigon_{1}\trigon_{1

Suppose that the system runs on a circuits and it operates until all a circuits die. Assume that the circuits are independent of one another.

On: What is the distribution (i.e., the ODF) of the lifetime of the system?

Arus: Let X; be the lifetime of the ith circuit.

Then the random vector (X,..., Xn) has all the information we need to determine the lifetime of the system.

We are definiting a random variable $Z = \max\{X_1, ..., X_n\}$.

We want $F_{\mathbb{Z}}(t)$.

 $F_{2}(t) = P(Z \le t)$ $= P(\max \{X_{1}, -, X_{2} \le t))$ $= P(X_{1} \le t, X_{2} \le t, -, X_{3} \le t) \quad (\text{by definition of max})$ $= P(X_{1} \le t, X_{2} \le t, -, X_{3} \le t) \quad (\text{by independence})$ $= P(X_{1} \le t) P(X_{2} \le t) \dots P(X_{n} \le t) \quad (\text{blc each } X_{1} \sim \text{Exp}(X))$ $= (1 - e^{-X_{1}}) (1 - e^{-X_{1}}) \dots (1 - e^{-X_{1}}) \quad (\text{blc each } X_{1} \sim \text{Exp}(X))$ $= (1 - e^{-X_{1}}) (1 - e^{-X_{1}}) \dots (1 - e^{-X_{1}}) \quad (\text{blc each } X_{1} \sim \text{Exp}(X))$ $= (1 - e^{-X_{1}}) \cap (1 - e^{-X_{1}}) \cap (1 - e^{-X_{1}}) \quad (\text{blc each } X_{1} \sim \text{Exp}(X))$ $= (1 - e^{-X_{1}}) \cap (1 - e^{-X_{1}$

MAXIMUM LIKELIHOOD ESTIMATION

DEF: A statistic & is just an function of a random sample.

DEF: A random sample is just a (typically finite)
sequence of independent and identically distributed randon variables.

EX: There are many possible statistics.

 $\Theta'(X'', ..., X'') = \frac{1}{r} \sum_{i=1}^{r} X_i = X'' = X$

Oa (X1, ---, Xn) = max { X, ..., Xn}

03(X1, --, Xn) = median &X1, ..., Xn}

 $\Theta_{4}(Y_{1},...,Y_{n}) = \frac{1}{n-1} \sum_{i=1}^{n} (Y_{i}-X_{i})^{2} = S^{2}$

BIG PITTURE QUESTION: How do I find good statistics,

i.e., statistics that are useful for estimating underlying population parameters?

DEF! the population parameters governing a rive are just those parameters that fully determine its distribution CDF.

EX: X~ N(m, o2) XN Sta(d, B, 8, 8) "stable r.v." X~ Exp(x) X~ Ber (p)

DEF: Suppose that X; is a r.v. with density (3) fx: (0; xi). For a random sample X1, X2, ..., Xn with common density fx. (0; xi), i=1,..., n, the wind density of likelihood function as just the plaint density of xi..., xn $L(\Theta; \{x_1, ..., x_n\}) = f_{X_1}(\theta; x_1) f_{X_2}(\theta; x_2) ... f_{X_n}(\theta; x_n)$ = TT fx:(0;x:) = Tf f(0; x;) (b/c identically) $\frac{3}{11}(i+1) = 2.3.4$ an: Suppose that you have a rondom sample X1,-, Xn. You regard it as fixed. How do you choose a O that best comports with, or is most compatible with, there date? IDEA: Choose the O that maximizes L(0, X, ..., Xn) realized values of our random sample So, we will choose ô = arg max L(0; X1, ..., Kn) The proposal!

problem: Maximizing or minimizing a function that is the product of functions is yucky. (why?)
Requires the use of the product rule which can be sloppy.

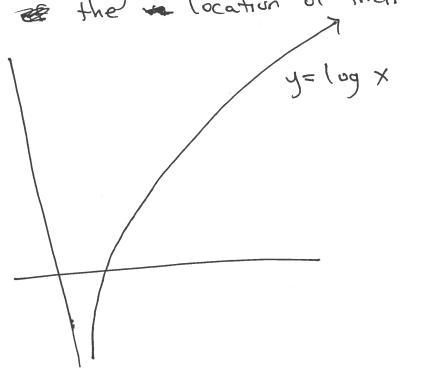
SOLUTION: Take the logarithm!

DEFINATION! The log-likelihood of the random sample $X_1, -1, X_n$, given θ , is the function $l(\theta; X_1, -1, X_n) = log(\prod_{i=1}^n log(\ell(\theta; X_i)))$ $= \sum_{i=1}^n log(\ell(\theta; X_i))$

On: Why was this "legal"?

Ans: Monotonic increasing functions do not change

Ans: Monotonic increasing functions of their extremo.



STEPS OF MLE

- 1) Form the likelihood function L.
- (a) Create the log-likelihood function l.
- (3) Compute the portial derivatives with respect to each unknown parameter.
- 4) Set each resulting expression equal to zero.
- 5) Solve the resulting equation of set of equations to identify critical points.
 - (6) Use second-order conditions (i.e., a second derivative test, e.g., might need to use Hessian) to determine which cotical point is the maximum. (Possibly need to check endpoints.)

6

EX: Suppose that X1,..., Xn is a random

sample from a normal distribution with

unknown mean μ and known of ventonce or.

() $L(\mu, \sigma^2; X_1, ..., X_n) = \frac{1}{\sigma \sqrt{2\pi}} e^{-\frac{(X_1^2 - \mu)^2}{2\sigma^2}}$

2 (M, 02; X1, ..., Xn) = = [log { otan e (Xi-M)? }

 $= \sum_{i=1}^{n} \{\log(\frac{1}{6\sqrt{2\pi}}) + \log(e^{-\frac{(X_i - \mu)^2}{2\sigma^2}})\}$ $= \sum_{i=1}^{n} \{\log(\sqrt{2\pi}) - \frac{(X_i - \mu)^2}{2\sigma^2}\}$

 $=-n\log(\sigma\sqrt{2\pi})-\frac{1}{2\sigma^2}\sum_{i=1}^{n}(\chi_{i}-\mu)^2$

 $\Rightarrow \begin{cases} \sum_{i=1}^{n} \chi_{i} \\ - n\mu = 0 \end{cases}$

 $\Rightarrow h = \frac{1}{2} \sum_{i=1}^{n} \chi_i = X^{n}$

6 - $\frac{n}{\sigma^2}$ < 0 => strictly concave down => $X_n = \hat{\mu}$ is a maximum

QUICK ASFOE: If you solve the same problem with or unknown, you will find the following joint solution:

 $\hat{x} = \frac{1}{x^{n}}$ $\hat{x} =$

Is this the formula for sample venince?

moral: MLE produces possible statistics that may not be the "best" in some way, e.g., they could be biased.

we now know how to find (possibly good) statistics. we might like to know things about them -e.g., their distributions.

It turns out that the (LT (Central Limit Theorem) plays a key role in describing the distribution of statistics like Xn or \$\frac{1}{2} \times \times

CENTRAL CIMIT THEOREM: Suppose that X1, ..., Xn is
a random sample, i.e., an independent and
identically distributed sequence of random variables.

Call the common mean µ of the random

vonables µ= E[X:]. Call the common (finite!) variance
by od= Var (X:) < 00. For large n (i.e., as n

tends to infinity), the following results

approximately hold:

 $\frac{1}{\sqrt{n}} = \frac{1}{\sqrt{n}} \frac{1}{\sqrt{$

EY: Suppose each person in MSDS 504 (and there are n=88) draw an X: $nExp(\lambda)$, where $\lambda=2$. They do so independently and we generate $\sum_{i=1}^{88} X_i^2$ with $X_i^2 nExp(\frac{1}{4}a)$.

- 1) What is the approximate distribution of $\sum_{i=1}^{88} x_i ?$
- a) what is its mean, venance, and standard devation?
- (3) Using the Empirical Pule, which symmetric sinterval would expect to find 5 X:

 interval would expect to find 5 X:

 in 95% of the time?
- The CLT says that $\sum_{i=1}^{88} X_i$ is approximately normally distributed.
- It has a mean equal to n = 88 times $E[X:] = \frac{1}{3}$, or 88 = 44. The Var $(X:) = \frac{1}{3}$ $(X:) = \frac{1}{3}$. Standard deviation $\sigma(X:) = \frac{1}{3}$
- By the Empirical Rule approximately 95% of the time the random sum 58 %; will be intoval [44-2522 44+2522].

EX: Suppose that Xi is a randomly-drawn Stanford-Binet IQ at test result. Note that E[X;J=100] and $\sigma_{X}=16$.

Suppose I take 9 MSDS students and assume they drawn from the general population. They are chosen at random and we compute the average ID for the group.

what is the threshold such that X_9 is underneath that threshold 85% of the time?

 $\Rightarrow \mathbb{E}[X_n] = \mathbb{E}[X_n] = 100.$

 $\forall \text{Var}(X_q) = \frac{16^2}{9} \implies \sqrt{x} = \sqrt{\frac{16^2}{9}} = \frac{16}{3}.$

Sometimes call this the "standard error"

=> gnorm (0.85, mean = 100, 5d = 16/3) \$ 105.52.

Or, using horrible table from 1968, 100 + 1.04 (16/3) 2 105.54.